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Report No.: SZEM170400351907
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FCC DFS TEST REPORT

Application No.:	SZEM1704003519RG
Applicant:	Saygus
Manufacturer:	Saygus
Factory:	Smart Gadgets (Shenzhen) , LTD
Product Name:	Saygus smartphone V-Squared
Model No.(EUT):	SG02
Trade Mark:	V Squared
FCC ID:	2ANBZ-F10104215
Standards:	47 CFR Part 15, Subpart E (2015) KDB 905462 D02 KDB 905462 D03
Date of Receipt:	2017-07-17
Date of Test:	2017-07-25 to 2017-08-29
Date of Issue:	2017-09-08
Test Result:	Pass*

*In the configuration tested, the EUT detailed in this report complied with the standards specified above.



Jack Zhang
EMC Laboratory Manager

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.

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2 Version

Revision Record				
Version	Chapter	Date	Modifier	Remark
01		2017-09-08		Original

Authorized for issue by:				
Tested By		Gray Gao		
		Gray Gao /Project Engineer		
Checked By		Eric Fu		
		Eric Fu /Reviewer		



3 Test Summary

Test Item	Test Requirement	Test method	Result
Dynamic Frequency Selection	15.407 (h)(2)	KDB 905462 D02 KDB 905462 D03	PASS



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5 General Information

5.1 Client Information

Applicant: Saygus
Address of Applicant: 10421 South Jordan Gateway, Suite 500, South Jordan, UT 84095
Manufacturer: Saygus
Address of Manufacturer: 10421 South Jordan Gateway, Suite 500, South Jordan, UT 84095
Factory: Smart Gadgets (Shenzhen) , LTD
Address of Factory: 912 Building 1 A, Hezheng-Huiyi Cheng, Xinhua Road, Xixiang Baoan District, Shenzhen, China

5.2 General Description of E.U.T.

Product Name: Saygus smartphone V-Squared
Model No.: SG02
Trade Mark: Saygus

5.3 Technical Specifications

Frequency Range:	Band	Mode	Frequency Range(MHz)	Number of channels
	Band I	IEEE 802.11a	5180-5240	4
		IEEE 802.11n/ac 20MHz	5180-5240	4
		IEEE 802.11n/ac 40MHz	5190-5230	2
		IEEE 802.11ac 80MHz	5210	1
	Band II	IEEE 802.11a	5260-5320	4
		IEEE 802.11n/ac 20MHz	5260-5320	4
		IEEE 802.11n/ac 40MHz	5270-5310	2
		IEEE 802.11ac 80MHz	5290	1
	Band III	IEEE 802.11a	5500-5700	11
		IEEE 802.11n/ac 20MHz	5500-5700	11
		IEEE 802.11n/ac 40MHz	5510-5670	5
		IEEE 802.11ac 80MHz	5530-5610	2
Type of Modulation:	IEEE 802.11a: OFDM(BPSK/QPSK/16QAM/64QAM) IEEE 802.11n: OFDM(BPSK/QPSK/16QAM/64QAM) IEEE 802.11ac: OFDM (BPSK/QPSK/16QAM/64QAM/256QAM)			
DFS mode	Client without radar detection			
Support TPC:	☐ Yes ☒ No			
Sample Type:	Portable production			
Antenna Type:	Integral			
Antenna Gain:	-1.0dBi			
Power Supply:	AC input: 100-240V 50/60Hz 0.5A DC output: 5V 2.4A or 9V 1.7A or 12V 1.3A			



5.4 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen Branch,
No. 1 Workshop, M-10, Middle Section, Science & Technology Park, Shenzhen, Guangdong, China.
518057.

Tel: +86 755 2601 2053 Fax: +86 755 2671 0594

No tests were sub-contracted.

5.5 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

- **CNAS (No. CNAS L2929)**

CNAS has accredited SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

- **A2LA (Certificate No. 3816.01)**

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation (A2LA). Certificate No. 3816.01.

- **VCCI**

The 10m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-823, R-4188, T-1153 and C-2383 respectively.

- **FCC –Designation Number: CN1178**

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been recognized as an accredited testing laboratory.

Designation Number: CN1178. Test Firm Registration Number: 406779.

- **Industry Canada (IC)**

Two 3m Semi-anechoic chambers and the 10m Semi-anechoic chamber of SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab have been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620C-1, 4620C-2, 4620C-3.



6 Dynamic Frequency Selection

6.1 Applicability of DFS requirements

Table 1: Applicability of DFS Requirements Prior to Use of a Channel

Requirement	Operational Mode		
	☐ Master	☒ Client Without Radar Detection	☐ Client With Radar Detection
Non-Occupancy Period	Yes	Not required	Yes
DFS Detection Threshold	Yes	Not required	Yes
Channel Availability Check Time	Yes	Not required	Not required
U-NII Detection Bandwidth	Yes	Not required	Yes

Table 2: Applicability of DFS requirements during normal operation

Requirement	Operational Mode	
	☐ Master Device or Client with Radar Detection	☒ Client Without Radar Detection
DFS Detection Threshold	Yes	Not required
Channel Closing Transmission Time	Yes	Yes
Channel Move Time	Yes	Yes
U-NII Detection Bandwidth	Yes	Not required

Additional requirements for devices with multiple bandwidth modes	☐ Master Device or Client with Radar Detection	☒ Client Without Radar Detection
U-NII Detection Bandwidth and Statistical Performance Check	All BW modes must be tested	Not required
Channel Move Time and Channel Closing Transmission Time	Test using widest BW mode available	Test using the widest BW mode available for the link
All other tests	Any single BW mode	Not required
Note: Frequencies selected for statistical performance check (Section 7.8.4) should include several frequencies within the radar detection bandwidth and frequencies near the edge of the radar detection bandwidth. For 802.11 devices it is suggested to select frequencies in each of the bonded 20 MHz channels and the channel center frequency.		

6.2 Limit

6.2.1 DFS Detection Thresholds

Table 3: DFS Detection Thresholds for Master Devices and Client Devices With Radar Detection

Maximum Transmit Power	Value (See Notes 1, 2, and 3)
EIRP $\geq$ 200 milliwatt	-64 dBm
EIRP $<$ 200 milliwatt and power spectral density $<$ 10 dBm/MHz	-62 dBm
EIRP $<$ 200 milliwatt that do not meet the power spectral density requirement	-64 dBm

Note 1: This is the level at the input of the receiver assuming a 0 dBi receive antenna.
Note 2: Throughout these test procedures an additional 1 dB has been added to the amplitude of the test transmission waveforms to account for variations in measurement equipment. This will ensure that the test signal is at or above the detection threshold level to trigger a DFS response.
Note3: EIRP is based on the highest antenna gain. For MIMO devices refer to KDB Publication 662911 D01.

6.2.2 DFS Response Requirements

Table 4: DFS Response Requirement Values

Parameter	Value
Non-occupancy period	Minimum 30 minutes
Channel Availability Check Time	60 seconds
Channel Move Time	10 seconds See Note 1.
Channel Closing Transmission Time	200 milliseconds + an aggregate of 60 milliseconds over remaining 10 second period. See Notes 1 and 2.
U-NII Detection Bandwidth	Minimum 100% of the U-NII 99% transmission power bandwidth. See Note 3.

Note 1: *Channel Move Time* and the *Channel Closing Transmission Time* should be performed with Radar Type 0. The measurement timing begins at the end of the Radar Type 0 burst.
Note 2: The *Channel Closing Transmission Time* is comprised of 200 milliseconds starting at the beginning of the *Channel Move Time* plus any additional intermittent control signals required facilitating a *Channel* move (an aggregate of 60 milliseconds) during the remainder of the 10 second period. The aggregate duration of control signals will not count quiet periods in between transmissions.
Note 3: During the *U-NII Detection Bandwidth* detection test, radar type 0 should be used. For each frequency step the minimum percentage of detection is 90 percent. Measurements are performed with no data traffic.



6.3 Parameters of radar test Waveforms

This section provides the parameters for required test waveforms, minimum percentage of successful detections, and the minimum number of trials that must be used for determining DFS conformance. Step intervals of 0.1 microsecond for Pulse Width, 1 microsecond for PRI, 1 MHz for chirp width and 1 for the number of pulses will be utilized for the random determination of specific test waveforms.

Table 5 Short Pulse Radar Test Waveforms

Radar Type	Pulse Width (μsec)	PRI (μsec)	Number of Pulses	Minimum Percentage of Successful Detection	Minimum Number of Trials
0	1	1428	18	See Note 1	See Note 1
1	1	Test A: 15 unique PRI values randomly selected from the list of 23 PRI values in Table 5a	$\text{Roundup} \left\{ \left(\frac{1}{360} \right) \cdot \left(\frac{19 \cdot 10^6}{\text{PRI}_{\mu\text{sec}}} \right) \right\}$	60%	30
		Test B: 15 unique PRI values randomly selected within the range of 518-3066 μsec, with a minimum increment of 1 μsec, excluding PRI values selected in Test A			
2	1-5	150-230	23-29	60%	30
3	6-10	200-500	16-18	60%	30
4	11-20	200-500	12-16	60%	30
Aggregate (Radar Types 1-4)				80%	120
Note 1: Short Pulse Radar Type 0 should be used for the detection bandwidth test, channel move time, and channel closing time tests.					

A minimum of 30 unique waveforms are required for each of the Short Pulse Radar Types 2 through 4. If more than 30 waveforms are used for Short Pulse Radar Types 2 through 4, then each additional waveform must also be unique and not repeated from the previous waveforms. If more than 30 waveforms are used for Short Pulse Radar Type 1, then each additional waveform is generated with Test B and must also be unique and not repeated from the previous waveforms in Tests A or B.



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Table 5a - Pulse Repetition Intervals Values for Test A

Pulse Repetition Frequency Number	Pulse Repetition Frequency (Pulses Per Second)	Pulse Repetition Interval (Microseconds)
1	1930.5	518
2	1858.7	538
3	1792.1	558
4	1730.1	578
5	1672.2	598
6	1618.1	618
7	1567.4	638
8	1519.8	658
9	1474.9	678
10	1432.7	698
11	1392.8	718
12	1355	738
13	1319.3	758
14	1285.3	778
15	1253.1	798
16	1222.5	818
17	1193.3	838
18	1165.6	858
19	1139	878
20	1113.6	898
21	1089.3	918
22	1066.1	938
23	326.2	3066



Table 6 – Long Pulse Radar Test Waveform

Radar Type	Pulse Width (μsec)	Chirp Width (MHz)	PRI (μsec)	Number of Pulses per <i>Burst</i>	Number of <i>Bursts</i>	Minimum Percentage of Successful Detection	Minimum Number of Trials
5	50-100	5-20	1000-2000	1-3	8-20	80%	30

The parameters for this waveform are randomly chosen. Thirty unique waveforms are required for the Long Pulse Radar Type waveforms. If more than 30 waveforms are used for the Long Pulse Radar Type waveforms, then each additional waveform must also be unique and not repeated from the previous waveforms.

Table 7 – Frequency Hopping Radar Test Waveform

Radar Type	Pulse Width (μsec)	PRI (μsec)	Pulses per Hop	Hopping Rate (kHz)	Hopping Sequence Length (msec)	Minimum Percentage of Successful Detection	Minimum Number of Trials
6	1	333	9	0.333	300	70%	30

For the Frequency Hopping Radar Type, the same *Burst* parameters are used for each waveform. The hopping sequence is different for each waveform and a 100-length segment is selected from the hopping sequence defined by the following algorithm:

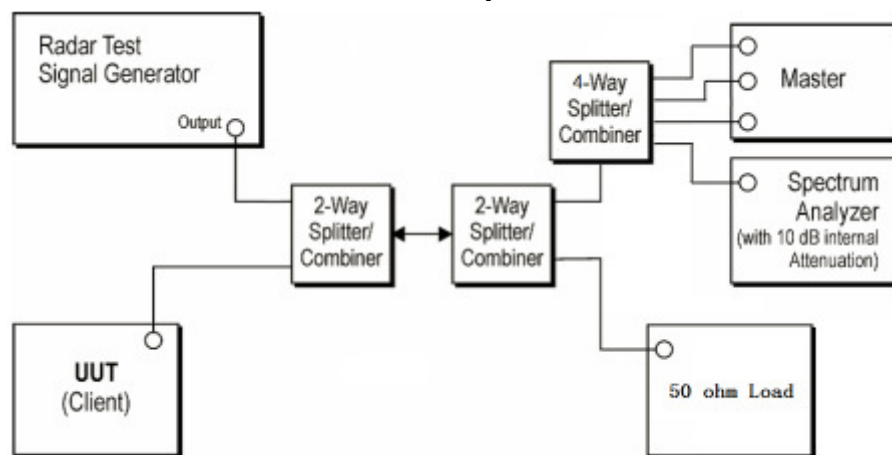
The first frequency in a hopping sequence is selected randomly from the group of 475 integer frequencies from 5250 – 5724 MHz. Next, the frequency that was just chosen is removed from the group and a frequency is randomly selected from the remaining 474 frequencies in the group. This process continues until all 475 frequencies are chosen for the set. For selection of a random frequency, the frequencies remaining within the group are always treated as equally likely.

6.4 Calibration of Radar Waveform

6.4.1 Radar Waveform Calibration Procedure

- 1) A 50 ohm load is connected in place of the spectrum analyzer, and the spectrum analyzer is connected to place of the master
- 2) The interference Radar Detection Threshold Level is $-62\text{dBm} + 0\text{dBi} + 1\text{dB} = -61\text{dBm}$ that had been taken into account the output power range and antenna gain.
- 3) The following equipment setup was used to calibrate the conducted radar waveform. A vector signal generator was utilized to establish the test signal level for radar type 0. During this process there were no transmissions by either the master or client device. The spectrum analyzer was switched to the zero spans (time domain) at the frequency of the radar waveform generator. Peak detection was used. The spectrum analyzer resolution bandwidth (RBW) and video bandwidth (VBW) were set to 3 MHz. The spectrum analyzer had offset -1.0dB to compensate RF cable loss 1.0dB .
- 4) The vector signal generator amplitude was set so that the power level measured at the spectrum analyzer was $-62\text{dBm} + 0\text{dBi} + 1\text{dB} = -61\text{dBm}$. Capture the spectrum analyzer plots on short pulse radar waveform.

6.4.2 Conducted Calibration Setup



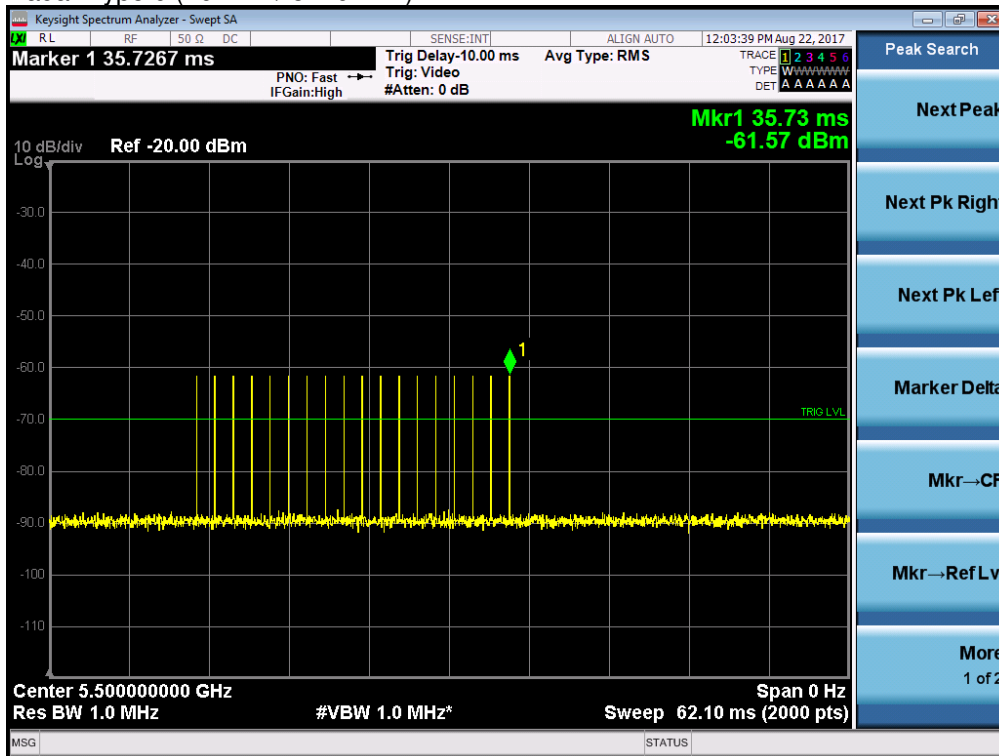
6.4.3 Calibration Deviation

There is no deviation with the original standard.



6.4.4 Radar Waveform Calibration Result

Radar Type 0 (40MHz / 5270MHz)





6.5 Test Procedure

- 1) The radar pulse generator is setup to provide a pulse at frequency that the master and client are operating. A type 0 radar pulse with a 1us pulse width and a 1428us PRI is used for the testing.
- 2) The vector signal generator is adjusted to provide the radar burst (18 pulses) at the level of approximately -61dBm at the antenna port of the master device.
- 3) A trigger is provided from the pulse generator to the DFS monitoring system in order to capture the traffic and the occurrence of the radar pulse.
- 4) EUT will associate with the master at channel. The file "iperf.exe" specified by the FCC is streamed from the PC 2 through the master and the client device to the PC 1 and played in full motion video using Media Player Classic Ver. 6.4.8.6 in order to properly load the network for the entire period of the test.
- 5) When radar burst with a level equal to the DFS Detection Threshold +1dB is generated on the operating channel of the U-NII device. At time T0 the radar waveform generator sends a burst of pulse of the radar waveform at Detection Threshold +1dB.
- 6) Observe the transmissions of the EUT at the end of the radar Burst on the Operating Channel. Measure and record the transmissions from the UUT during the observation time (Channel Move Time). One 15 seconds plot is reported for the Short Pulse Radar Type 0. The plot for the Short Pulse Radar Types start at the end of the radar burst. The Channel Move Time will be calculated based on the zoom in 600ms plot of the Short Pulse Radar Type.
- 7) Measurement of the aggregate duration of the Channel Closed Transmission Time method. With the spectrum analyzer set to zero span tuned to the center frequency of the EUT operating channel at the radar simulated frequency, peak detection, and max hold, the dwell time per bin is given by: $Dwell (0.3ms) = S (12000ms) / B (4000)$; where Dwell is the dwell time per spectrum analyzer sampling bin, S is sweep time and B is the number of spectrum analyzer sampling bins. An upper bound of the aggregate duration of the intermittent control signals of Channel Closing Transmission Time is calculated by: $C (ms) = N \times Dwell (0.3ms)$; where C is the Closing Time, N is the number of spectrum analyzer sampling bins (intermittent control signals) showing a U-NII transmission and Dwell is the dwell time per bin.
- 8) Measurement the EUT for more than 30 minutes following the channel move time to verify that no transmission or beacons occur on this channel.

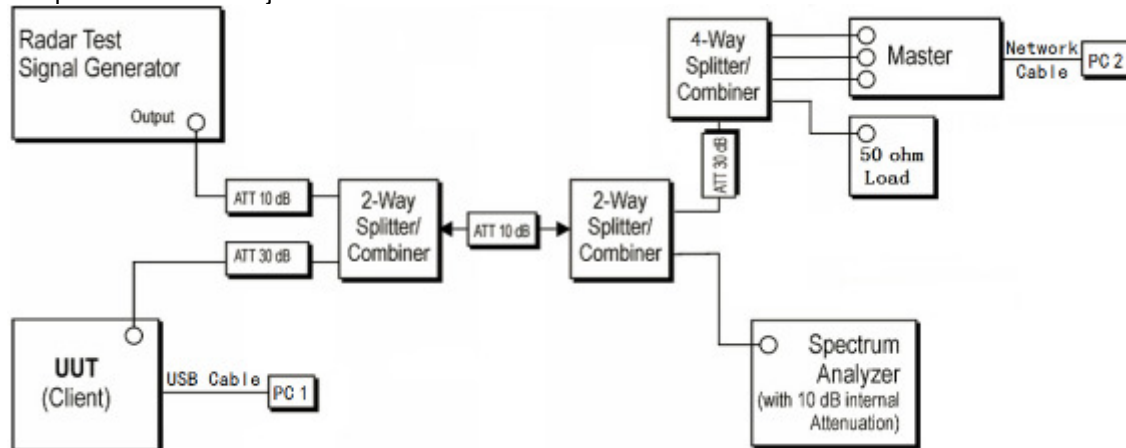


6.6 Test Equipment

RF test system						
Item	Test Equipment	Manufacturer	Model No.	Inventory No.	Cal. Date (yyyy-mm-dd)	Cal. Due date (yyyy-mm-dd)
1	EXA Signal Analyzer (10Hz-44GHz)	KEYSIGHT	N9010A	SEM004-12	2017-07-17	2018-07-16
2	Signal Generator(9kHz-3GHz)	KEYSIGHT	N5171B	SEM006-13	2017-07-17	2018-07-16
3	MXG Vector Signal Generator	KEYSIGHT	N5182A	SEM006-14	2017-06-05	2018-06-04
4	DC Power Supply	KEYSIGHT	E3642A	SEM011-07	2017-06-05	2018-06-04
5	Manual Step Attenuator	KEYSIGHT	8494B	SEM021-05	2017-07-17	2018-07-16
6	Manual Step Attenuator	KEYSIGHT	8496B	SEM021-06	2017-07-17	2018-07-16
7	Power Sensor	KEYSIGHT	U2021XA	SEM009-01	2016-10-09	2017-10-09
8	Power Sensor	KEYSIGHT	U2021XA	SEM009-04	2016-10-09	2017-10-09
9	Power Sensor	KEYSIGHT	U2021XA	SEM009-13	2017-06-21	2018-06-20
10	Power Sensor	KEYSIGHT	U2021XA	SEM009-14	2017-06-21	2018-06-20
11	Bluetooth Tester	Rohde & Schwarz	CBT	W060-01	2017-06-21	2018-06-21
12	Universal Radio Communication Tester	Rohde & Schwarz	CMW 500	SEM010-03	2017-04-14	2018-04-13
13	Measurement Software	JS Tonscend	JS1120-2 BT/WIFI V2.6	N/A	N/A	N/A

6.7 Test Setup

☒ Setup for Client with injection at the Master





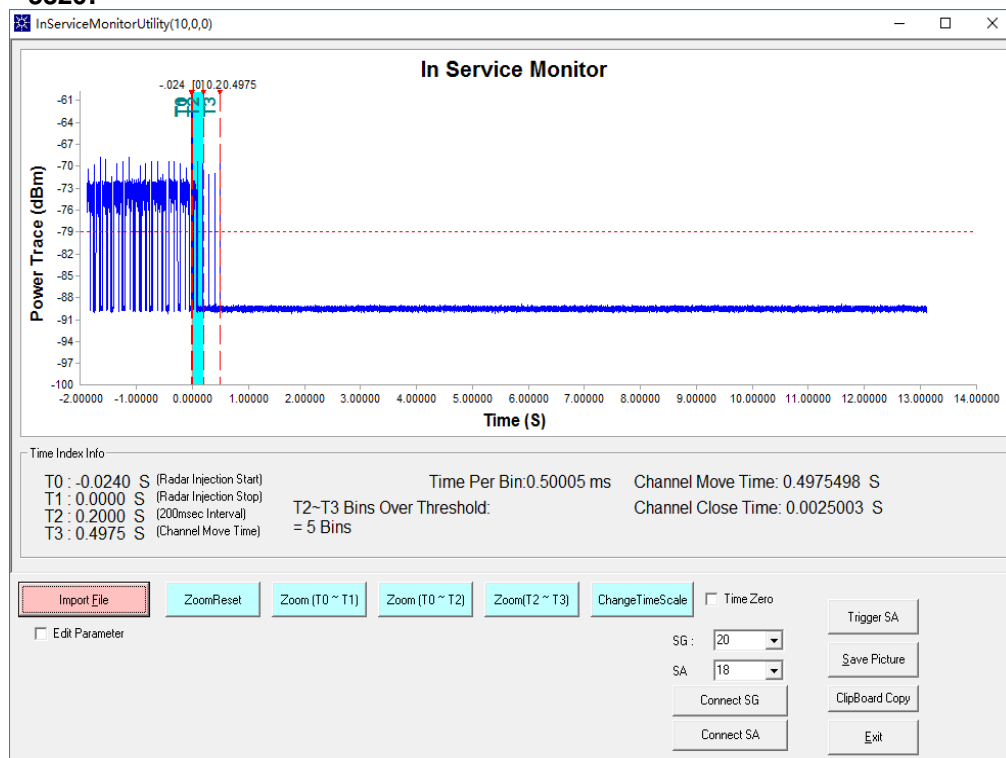
6.8 Test Result

Test Data: Antenna 1

BW/Channel	Test Item	Test Result	Limit	Results
20MHz/5320MHz	Channel Move Time	0.498 s	< 10 s	Pass
	Channel Closing Transmission Time	25 ms	< 60ms	Pass
40MHz/5500MHz	Channel Move Time	0.482 s	< 10 s	Pass
	Channel Closing Transmission Time	25 ms	< 60ms	Pass

Test plots as follows:

5320:





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